


<b>Search Notes</b>  	<b>Application/Control No.</b>  10589861	<b>Applicant(s)/Patent Under Reexamination</b>  NYU, TAKAYUKI
	<b>Examiner</b>  Michael Mapa	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	410, 411, 456.4, 561	10/24/08	/MM/
370	338	10/24/08	/MM/
379	114.14, 142.05, 194	10/24/08	/MM/

SEARCH NOTES		
Search Notes	Date	Examiner
INVENTOR SEARCH	10/24/08	/MM/
EAST SEARCH	10/24/08	/MM/
UPDATED EAST SEARCH	03/27/09	/MM/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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